

April 1988 Revised August 1999

74F273 Octal D-Type Flip-Flop

General Description

The 74F273 has eight edge-triggered D-type flip-flops with individual D inputs and Q outputs. The common buffered Clock (CP) and Master Reset (MR) inputs load and reset (clear) all flip-flops simultaneously.

The register is fully edge-triggered. The state of each D input, one setup time before the LOW-to-HIGH clock transition, is transferred to the corresponding flip-flop's Q output.

All outputs will be forced LOW independently of Clock or Data inputs by a LOW voltage level on the $\overline{\text{MR}}$ input. The device is useful for applications where the true output only is required and the Clock and Master Reset are common to all storage elements.

Features

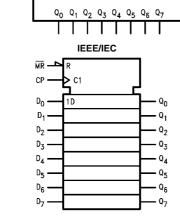
- Ideal buffer for MOS microprocessor or memory
- Eight edge-triggered D-type flip-flops
- Buffered common clock
- Buffered, asynchronous Master Reset
- See 74F377 for clock enable version
- See 74F373 for transparent latch version
- See 74F374 for 3-STATE version



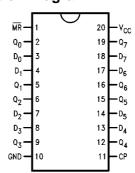
Order Number	Package Number	Package Description
74F273SC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide
74F273SJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74F273PC	N20A	20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Logic Symbols



Connection Diagram



Unit Loading/Fan Out

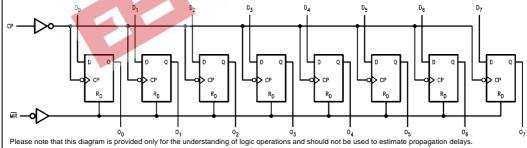
Din Names	December 1	U.L.	Input I _{IH} /I _{IL}		
Pin Names	Description	HIGH/LOW	Output I _{OH} /I _{OL}		
D ₀ –D ₇	Data Inputs	1.0/1.0	20 μA/-0.6 mA		
MR	Master Reset (Active LOW)	1.0/1.0	20 μA/-0.6 mA		
CP	Clock Pulse Input (Active Rising Edge)	1.0/1.0	20 μA/–0.6 mA		
Q_0-Q_7	Data Outputs	50/33.3	-1 mA/20 mA		

Mode Select-Function Table

On another Marks		Output		
Operating Mode	MR	СР	D _n	Q _n
Reset (Clear)	L	Х	X	L
Load "1"	Н	~	h	Н
Load "0"	Н	- 2he	7.0 T	7

- H = HIGH Voltage Level steady state
 h = HIGH Voltage Level one setup time prior to the LOW-to-HIGH clock transitio
 L = LOW Voltage Level steady state
 I = LOW Voltage Level one setup time prior to the LOW-to-HIGH clock transition
- X = Immaterial
- ∠ = LOW-to-HIGH clock transition

Logic Diagram



Absolute Maximum Ratings(Note 1)

Recommended Operating Conditions

Storage Temperature $-65^{\circ}\text{C} \text{ to } +150^{\circ}\text{C}$

Ambient Temperature under Bias -55° C to $+125^{\circ}$ C Junction Temperature under Bias -55° C to $+150^{\circ}$ C

 $\begin{array}{lll} \text{V}_{\text{CC}} \text{ Pin Potential to Ground Pin} & -0.5 \text{V to } +7.0 \text{V} \\ \text{Input Voltage (Note 2)} & -0.5 \text{V to } +7.0 \text{V} \\ \text{Input Current (Note 2)} & -30 \text{ mA to } +5.0 \text{ mA} \\ \end{array}$

Voltage Applied to Output

in HIGH State (with $V_{CC} = 0V$)

Standard Output -0.5V to V_{CC} 3-STATE Output -0.5V to +5.5V

Current Applied to Output

in LOW State (Max) twice the rated I_{OL} (mA) ESD Last Passing Voltage (min) 4000V

Free Air Ambient Temperature $0^{\circ}\text{C} \text{ to } +70^{\circ}\text{C}$ Supply Voltage +4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

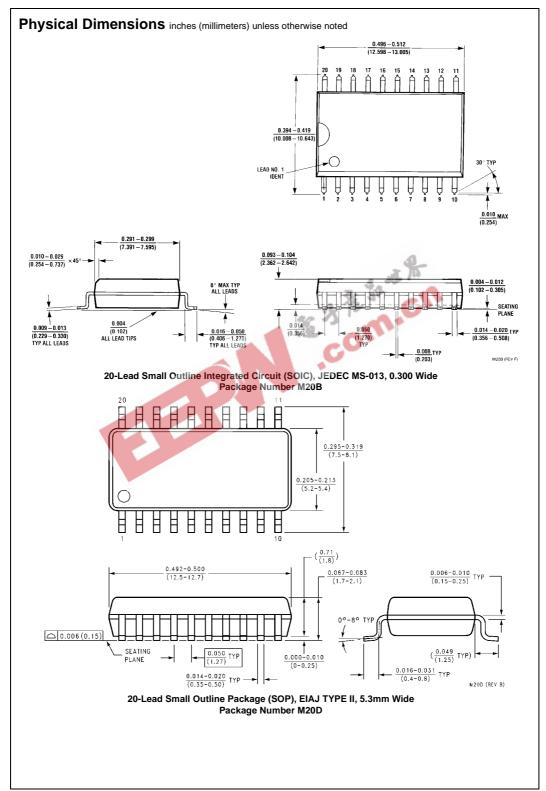
DC Electrical Characteristics

Symbol	Parameter		Min	Тур	Max	Units	Vcc	Conditions	
V _{IH}	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signal	
V _{IL}	Input LOW Voltage				0.8	V		Recognized as a LOW Signal	
V _{CD}	Input Clamp Diode Voltage				-1.2	V	Min	i _{IN} = -18 mA	
V _{OH}	Output HIGH 109	% V _{CC}	2.5		V31	V	Min	I _{OH} = -1 mA	
	Voltage 5%	% V _{CC}	2.7		100	0	IVIIII	IOH I IIIV	
V _{OL}	Output LOW 109	% V _{CC}			0.5	V	Min	I _{OL} = 20 mA	
	Voltage 59	% V _{CC}			0.5	ľ	IVIIII	10L - 20 111A	
I _{IH}	Input HIGH				5.0	μА	Max	V _{IN} = 2.7V	
	Current				0.0	μι	IVIGA	VIN - 2.7 V	
I _{BVI}	Input HIGH Current				7.0	μА	Max	V _{IN} = 7.0V	
	Breakdown Test					μ.,	max	- IIV	
I _{CEX}	Output HIGH				50	μА	Max	$V_{OUT} = V_{CC}$	
	Leakage Current					p		55.	
V_{ID}	Input Leakage		4.75			V	0.0	$I_{ID} = 1.9 \mu\text{A}$	
	Test		4.70			•	0.0	All other pins grounded	
l _{OD}	Output Leakage				3.75	μА	0.0	V _{IOD} = 150 mV	
	Circuit Current				0.70	μι	0.0	All other pins grounded	
I _{IL}	Input LOW Current				-0.6	mA	Max	V _{IN} = 0.5V	
los	Output Short-Circuit Current		-60		-150	mA	Max	V _{OUT} = 0V	
I _{CCH}	Power Supply Current	_			44	mA	Max	CP =	
I _{CCL}					56	IIIA	ividX	$D_n = \overline{MR} = HIGH$	

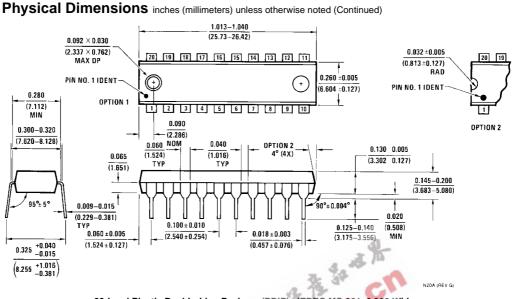
			T _A = +25°C		$T_A = -55^{\circ}C$	C to +125°C	T _A = 0°C	to +70°C	
Combal	Parameter		$V_{CC} = +5.0V$ $C_L = 50 \text{ pF}$			$V_{CC} = 5.0V$ $C_L = 50 \text{ pF}$		$V_{CC} = 5.0V$ $C_L = 50 \text{ pF}$	
Symbol									
		Min	Тур	Max	Min	Max	Min	Max	
f_{MAX}	Maximum Clock Frequency	160			95		130		М
t _{PLH}	Propagation Delay	3.0		7.0	2.5	9.5	2.5	7.5	_
t _{PHL}	Clock to Output	4.0		9.00	3.0	11.0	3.5	9.0	r
t _{PLH}	Propagation Delay MR to Output	4.5		9.5	3.0	11.0	4.0	10.0	n

AC Operating Requirements

		T,	= +25°C	T _A = -55°C	to +125°C	T _A = 0°C	to +70°C	
Symbol	Parameter	$V_{CC} = +5.0V$		$V_{CC}=5.0V$		$V_{CC} = 5.0V$		Units
		Min	Max	Min	Max	Min	Max	
t _S (H)	Setup Time, HIGH or LOW	3.0		3.5		3.0		
t _S (L)	Data to CP	3.5		4.0	43	3.5		ns
t _H (H)	Hold Time, HIGH or LOW	0.5		1.0	AP	0.5		115
$t_H(L)$	Data to CP	1.0		1.0	-	1.0		
t _W (L)	MR Pulse Width, LOW	6.0	A.	4.0		6.0		ns
t _W (H)	CP Pulse Width	6.0	20 13	5.0		6.0		ns
$t_W(L)$	HIGH or LOW	6.0	32	5.0		6.0		113
t _{REC}	Recovery Time, MR to CP	3.0	100	4 .5		3.5		ns







20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide Package Number N20A

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